Search Notes		
	BIAR BEIN DIBBI IBIN 11611 HAIF IBB	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,820	CHI, CHAO-WEN	
Examiner	Art Unit	
Jeffrey Donels	2837	

	SEARCHED		
Class	Subclass	Date	Examiner
84`	645	12/12/2005	JWD
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INT	NTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEAR (INCLUDING S	CH NOTES EARCH STRATEGY	
	DATE	EXMR
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